## NSN 6625-01-355-2947

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√iew Online	e at https://ae	robasegroup	.kr/nsn/6625	-01-355-2947

Shelf Life:

N/a

**Unit Of Measure:** 

1 ea

Demilitarization:

No

Fiig:

T228-a

Hazmat:

Yes

Repairability:

If condemned or uneconomically repairable, then dispose at intermediate level.